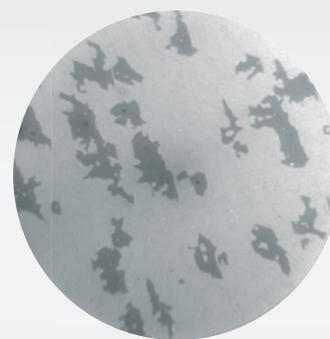
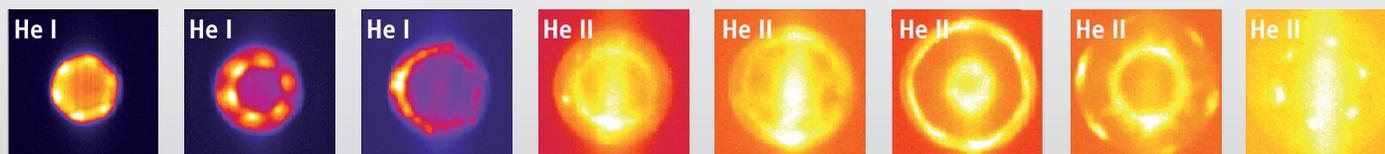


State-of-the-art Instrumentation for Nanotechnology

Aberration Corrected LEEM/PEEM with 2 nm lateral resolution

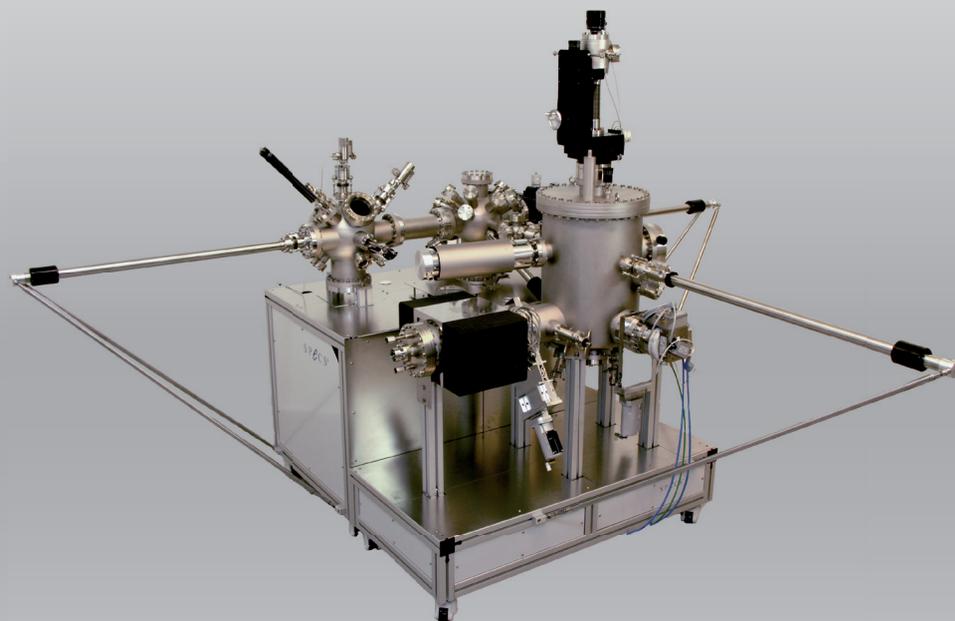


LEEM on Graphene/SiC(0001)
FOV 12 μ m



Energy Filtered PEEM on Graphene/SiC(0001): Momentum Plots at different Constant Kinetic Energies (in 5 eV steps)

Combined STM/AFM/XPS/UPS/MBE Systems with atomic resolution



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ISO 9001 Certificate

For References refer to our web page.

